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## Overview

### Basic Features

- High-Side Switch with Diagnosis and Embedded Protection
- Part of PROFET™+2 Family
- ReverSave™ for low power dissipation in Reverse Polarity
- Switch ON capability while Inverse Current condition (InverseON)
- Green Product (RoHS compliant)
- Qualified in accordance with AEC Q100 grade 1

### Protection Features

- Absolute and dynamic temperature limitation with controlled restart
- Overcurrent protection (tripping) with Intelligent Restart Control
- Undervoltage shutdown
- Overvoltage Protection with external components

### Diagnostic Features

- Proportional load current sense
- Open Load in ON and OFF state
- Short circuit to ground and battery

### Description

The BTS7020-2EPA is a Smart High-Side Power Switch, providing protection functions and diagnosis. The device is integrated in SMART7 technology.

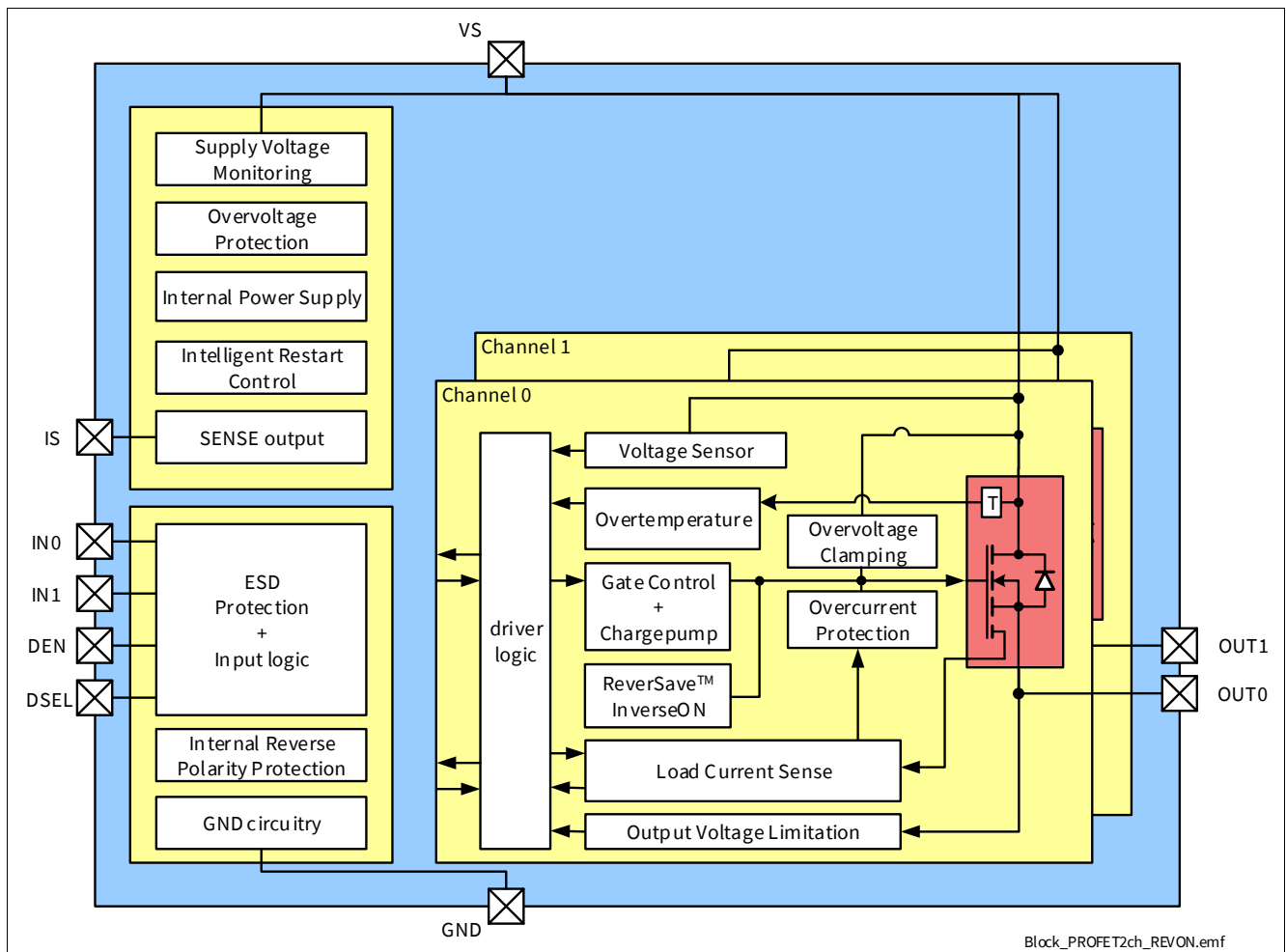
**Table 1 Product Summary**

| Parameter   | Symbol            | Values          |
|---|-------------------|-----------------|
| Minimum Operating voltage (at switch ON)                  | $V_{S(OP)}$       | 4.1 V           |
| Minimum Operating voltage (cranking)                      | $V_{S(UV)}$       | 3.1 V           |
| Maximum Operating voltage                                 | $V_S$             | 28 V            |
| Minimum Overvoltage protection ( $T_J = 25\text{ °C}$ )   | $V_{DS(CLAMP)}$   | 35 V            |
| Maximum current in Sleep mode ( $T_J \leq 85\text{ °C}$ ) | $I_{VS(SLEEP)}$   | 1 $\mu$ A       |
| Maximum operative current                                 | $I_{GND(ACTIVE)}$ | 4 mA            |
| Maximum ON-state resistance ( $T_J = 150\text{ °C}$ )     | $R_{DS(ON)}$      | 23.7 m $\Omega$ |
| Nominal load current ( $T_A = 85\text{ °C}$ )             | $I_{L(NOM)}$      | 5 A             |
| Typical current sense ratio at $I_L = I_{L(NOM)}$         | $k_{ILIS}$        | 3700            |

**Block Diagram and Terms**

**2 Block Diagram and Terms**

**2.1 Block Diagram**

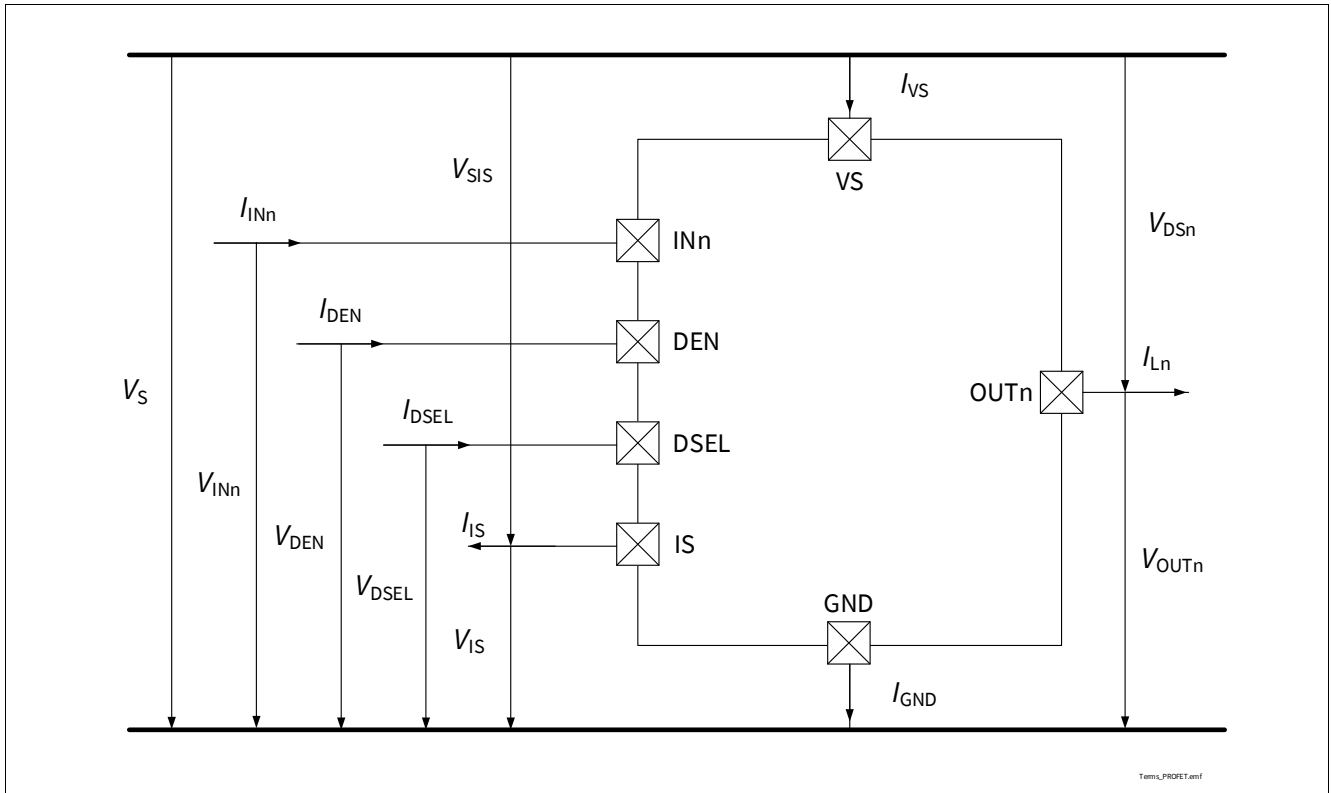


**Figure 2 Block Diagram of BTS7020-2EPA**

**Block Diagram and Terms**

**2.2 Terms**

**Figure 3** shows all terms used in this data sheet, with associated convention for positive values.



**Figure 3 Voltage and Current Convention**

Pin Configuration

### 3 Pin Configuration

#### 3.1 Pin Assignment

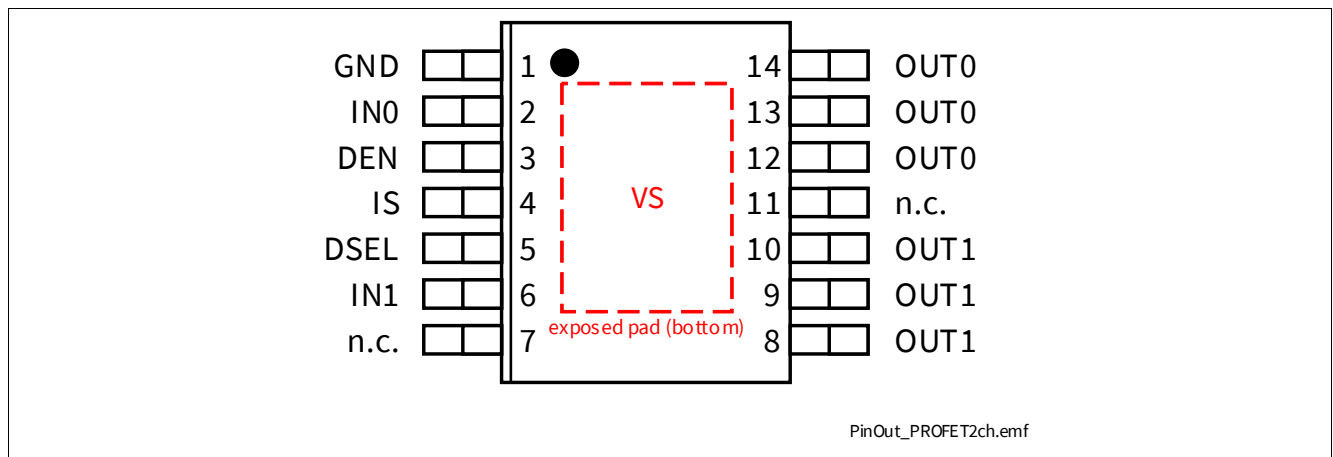


Figure 4 Pin Configuration



**Pin Configuration**

**3.2 Pin Definitions and Functions**

**Table 2 Pin Definition**

| <b>Pin</b>  | <b>Symbol</b>       | <b>Function</b>   |
|-------------|---------------------|---|
| EP          | VS<br>(exposed pad) | <b>Supply Voltage</b><br>Battery voltage  |
| 1           | GND                 | <b>Ground</b><br>Signal ground  |
| 2, 6        | INn                 | <b>Input Channel n</b><br>Digital signal to switch ON channel n (“high” active)<br>If not used: connect with a 10 kΩ resistor either to GND pin or to module ground   |
| 3           | DEN                 | <b>Diagnostic Enable</b><br>Digital signal to enable device diagnosis (“high” active) and to clear the protection counter of channel selected with DSEL pin<br>If not used: connect with a 10 kΩ resistor either to GND pin or to module ground |
| 4           | IS                  | <b>SENSE current output</b><br>Analog/digital signal for diagnosis<br>If not used: left open  |
| 5           | DSEL                | <b>Diagnosis Selection</b><br>Digital signal to select one channel to perform ON and OFF state diagnosis (“high” active)<br>If not used: connect with a 10 kΩ resistor either to GND pin or to module ground                                    |
| 7, 11       | n.c.                | Not connected, internally not bonded  |
| 8-10, 12-14 | OUTn                | <b>Output n</b><br>Protected high-side power output channel n <sup>1)</sup>   |

1) All output pins of the channel must be connected together on the PCB. All pins of the output are internally connected together. PCB traces have to be designed to withstand the maximum current which can flow

**General Product Characteristics**

**4 General Product Characteristics**

**4.1 Absolute Maximum Ratings - General**

**Table 3 Absolute Maximum Ratings<sup>1)</sup>**

$T_J = -40\text{ °C}$  to  $+150\text{ °C}$ ; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)

| Parameter                                   | Symbol          | Values |      |      | Unit | Note or Test Condition   | Number     |
|---|-----------------|--------|------|------|------|--|------------|
|   |                 | Min.   | Typ. | Max. |      |  |            |
| <b>Supply pins</b>                          |                 |        |      |      |      |  |            |
| Power Supply Voltage                        | $V_S$           | -0.3   | –    | 28   | V    | –  | P_4.1.0.1  |
| Load Dump Voltage                           | $V_{BAT(LD)}$   | –      | –    | 35   | V    | suppressed Load Dump acc. to ISO16750-2 (2010).<br>$R_f = 2\ \Omega$                               | P_4.1.0.3  |
| Supply Voltage for Short Circuit Protection | $V_{BAT(SC)}$   | 0      | –    | 24   | V    | Setup acc. to AEC-Q100-012   | P_4.1.0.25 |
| Reverse Polarity Voltage                    | $-V_{BAT(REV)}$ | –      | –    | 16   | V    | $t \leq 2\text{ min}$<br>$T_A = +25\text{ °C}$<br>Setup as described in <a href="#">Chapter 10</a> | P_4.1.0.5  |
| Current through GND Pin                     | $I_{GND}$       | -50    | –    | 50   | mA   | $R_{GND}$ according to <a href="#">Chapter 10</a>  | P_4.1.0.9  |

**Logic & control pins (Digital Input = DI)**

**DI = INn, DEN, DSEL**

|  |          |    |   |    |    |  |            |
|--|----------|----|---|----|----|--|------------|
| Current through DI Pin                           | $I_{DI}$ | -1 | – | 2  | mA | <sup>2)</sup>                          | P_4.1.0.14 |
| Current through DI Pin Reverse Battery condition | $I_{DI}$ | -1 | – | 10 | mA | <sup>2)</sup><br>$t \leq 2\text{ min}$ | P_4.1.0.36 |

**IS pin**

|                        |          |      |   |                       |    |                            |            |
|------------------------|----------|------|---|-----------------------|----|----------------------------|------------|
| Voltage at IS Pin      | $V_{IS}$ | -1.5 | – | $V_S$                 | V  | $I_{IS} = 10\ \mu\text{A}$ | P_4.1.0.16 |
| Current through IS Pin | $I_{IS}$ | -25  | – | $I_{IS(SAT),M}$<br>AX | mA | –                          | P_4.1.0.18 |

**Temperatures**

|                      |           |     |   |     |    |   |            |
|----------------------|-----------|-----|---|-----|----|---|------------|
| Junction Temperature | $T_J$     | -40 | – | 150 | °C | – | P_4.1.0.19 |
| Storage Temperature  | $T_{STG}$ | -55 | – | 150 | °C | – | P_4.1.0.20 |

**ESD Susceptibility**



**General Product Characteristics**

**Table 3 Absolute Maximum Ratings<sup>1)</sup>** (continued)

$T_J = -40\text{ °C}$  to  $+150\text{ °C}$ ; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)

| Parameter  | Symbol                | Values |      |      | Unit | Note or Test Condition | Number     |
|--|-----------------------|--------|------|------|------|------------------------|------------|
|  |                       | Min.   | Typ. | Max. |      |                        |            |
| ESD Susceptibility all Pins (HBM)                          | $V_{ESD(HBM)}$        | -2     | –    | 2    | kV   | HBM <sup>3)</sup>      | P_4.1.0.21 |
| ESD Susceptibility OUTn vs GND and VS connected (HBM)      | $V_{ESD(HBM)_{OU}}_T$ | -4     | –    | 4    | kV   | HBM <sup>3)</sup>      | P_4.1.0.22 |
| ESD Susceptibility all Pins (CDM)                          | $V_{ESD(CDM)}$        | -500   | –    | 500  | V    | CDM <sup>4)</sup>      | P_4.1.0.23 |
| ESD Susceptibility Corner Pins (CDM)<br>(pins 1, 7, 8, 14) | $V_{ESD(CDM)_{CR}}_N$ | -750   | –    | 750  | V    | CDM <sup>4)</sup>      | P_4.1.0.24 |

- 1) Not subject to production test - specified by design.
- 2) Maximum  $V_{DI}$  to be considered for Latch-Up tests: 5.5 V
- 3) ESD susceptibility, HBM according to ANSI/ESDA/JEDEC JS001 (1.5 kΩ, 100 pF)
- 4) ESD susceptibility, Charged Device Model “CDM” according JEDEC JESD22-C101

**Notes**

1. Stresses above the ones listed here may cause permanent damage to the device. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.
2. Integrated protection functions are designed to prevent IC destruction under fault conditions described in the data sheet. Fault conditions are considered as “outside” normal operating range. Protection functions are not designed for continuous repetitive operation.

**4.2 Absolute Maximum Ratings - Power Stages**

**4.2.1 Power Stage - 20 mΩ**

**Table 4 Absolute Maximum Ratings<sup>1)</sup>**

$T_J = -40\text{ °C}$  to  $+150\text{ °C}$ ; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)

| Parameter                               | Symbol   | Values |      |      | Unit | Note or Test Condition  | Number    |
|---|----------|--------|------|------|------|---|-----------|
|   |          | Min.   | Typ. | Max. |      |   |           |
| Maximum Energy Dissipation Single Pulse | $E_{AS}$ | –      | –    | 42   | mJ   | $I_L = 2 \cdot I_{L(NOM)}$<br>$T_{J(0)} = 150\text{ °C}$<br>$V_S = 28\text{ V}$ | P_4.2.4.1 |

**General Product Characteristics**

**Table 4 Absolute Maximum Ratings<sup>1)</sup>** (continued)

$T_J = -40\text{ °C}$  to  $+150\text{ °C}$ ; all voltages with respect to ground, positive current flowing into pin (unless otherwise specified)

| Parameter                                   | Symbol   | Values |      |                      | Unit | Note or Test Condition  | Number    |
|---|----------|--------|------|----------------------|------|---|-----------|
|   |          | Min.   | Typ. | Max.                 |      |   |           |
| Maximum Energy Dissipation Repetitive Pulse | $E_{AR}$ | –      | –    | 18                   | mJ   | $I_L = I_{L(NOM)}$<br>$T_{J(0)} = 85\text{ °C}$<br>$V_S = 13.5\text{ V}$<br>1M cycles | P_4.2.4.2 |
| Load Current                                | $ I_L $  | –      | –    | $I_{L(OVL),M}$<br>AX | A    | –   | P_4.2.4.3 |

1) Not subject to production test, specified by design.

**4.3 Functional Range**

**Table 5 Functional Range - Supply Voltage and Temperature<sup>1)</sup>**

| Parameter   | Symbol           | Values |      |      | Unit | Note or Test Condition                             | Number    |
|---|------------------|--------|------|------|------|--|-----------|
|   |                  | Min.   | Typ. | Max. |      |  |           |
| Supply Voltage Range for Normal Operation         | $V_{S(NOR)}$     | 6      | 13.5 | 18   | V    | –  | P_4.3.0.1 |
| Lower Extended Supply Voltage Range for Operation | $V_{S(EXT,LOW)}$ | 3.1    | –    | 6    | V    | <sup>2)3)</sup><br>(parameter deviations possible) | P_4.3.0.2 |
| Upper Extended Supply Voltage Range for Operation | $V_{S(EXT,UP)}$  | 18     | –    | 28   | V    | <sup>3)</sup><br>(parameter deviations possible)   | P_4.3.0.3 |
| Junction Temperature                              | $T_J$            | -40    | –    | 150  | °C   | –  | P_4.3.0.5 |

1) Not subject to production test - specified by design.

2) In case of  $V_S$  voltage decreasing:  $V_{S(EXT,LOW),MIN} = 3.1\text{ V}$ . In case of  $V_S$  voltage increasing:  $V_{S(EXT,LOW),MIN} = 4.1\text{ V}$

3) Protection functions still operative

*Note: Within the functional or operating range, the IC operates as described in the circuit description. The electrical characteristics are specified within the conditions given in the Electrical Characteristics tables.*

**General Product Characteristics**

**4.4 Thermal Resistance**

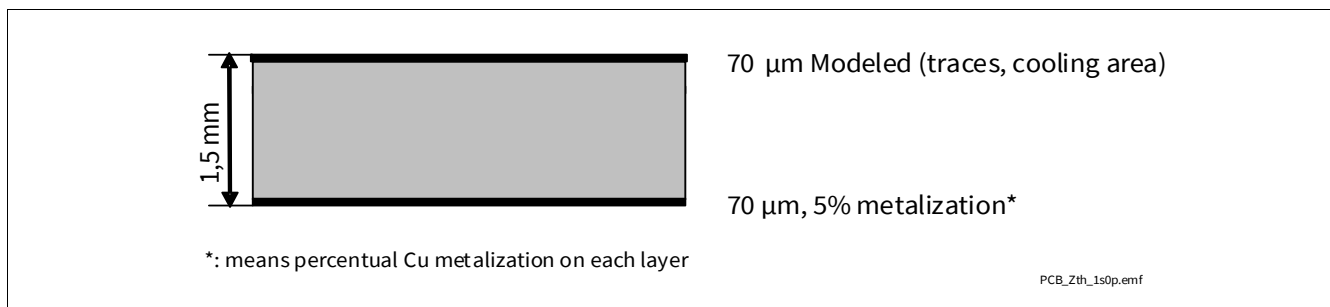
Note: This thermal data was generated in accordance with JEDEC JESD51 standards. For more information, go to [www.jedec.org](http://www.jedec.org).

**Table 6 Thermal Resistance<sup>1)</sup>**

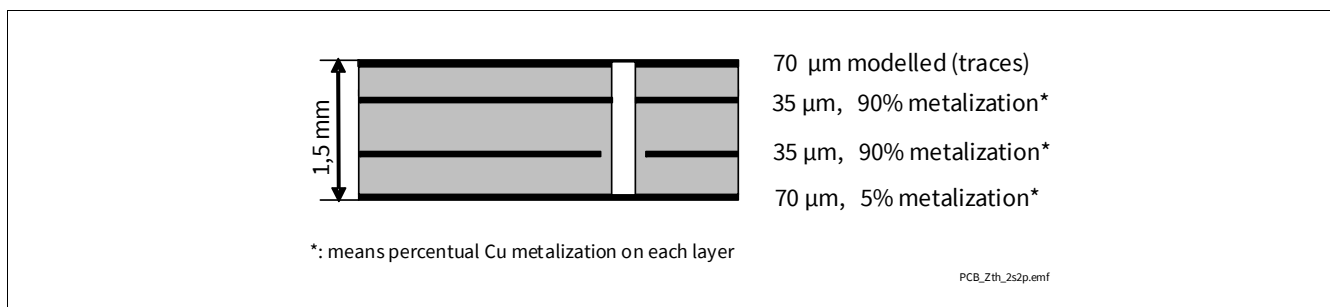
| Parameter                                       | Symbol        | Values |      |      | Unit | Note or Test Condition                    | Number    |
|---|---------------|--------|------|------|------|---|-----------|
|   |               | Min.   | Typ. | Max. |      |   |           |
| Thermal Characterization Parameter Junction-Top | $\Psi_{JTOP}$ | –      | 1.8  | 3    | K/W  | <sup>2)</sup>                             | P_4.4.0.1 |
| Thermal Resistance Junction-to-Case             | $R_{thJC}$    | –      | 1.1  | 1.9  | K/W  | <sup>2)</sup><br>simulated at exposed pad | P_4.4.0.2 |
| Thermal Resistance Junction-to-Ambient          | $R_{thJA}$    | –      | 31.1 | –    | K/W  | <sup>2)</sup>                             | P_4.4.0.3 |

- 1) Not subject to production test - specified by design.
- 2) Specified  $R_{thJA}$  value is according to Jedec JESD51-2,-5,-7 at natural convection on FR4 2s2p board; the Product (Chip + Package) was simulated on a 76.2 × 114.3 × 1.5 mm board with 2 inner copper layers (2 × 70 μm Cu, 2 × 35 μm Cu). Where applicable a thermal via array under the exposed pad contacted the first inner copper layer. Simulation done at  $T_A = 105^{\circ}C$ ,  $P_{DISSIPATION} = 1 W$ .

**4.4.1 PCB Setup**

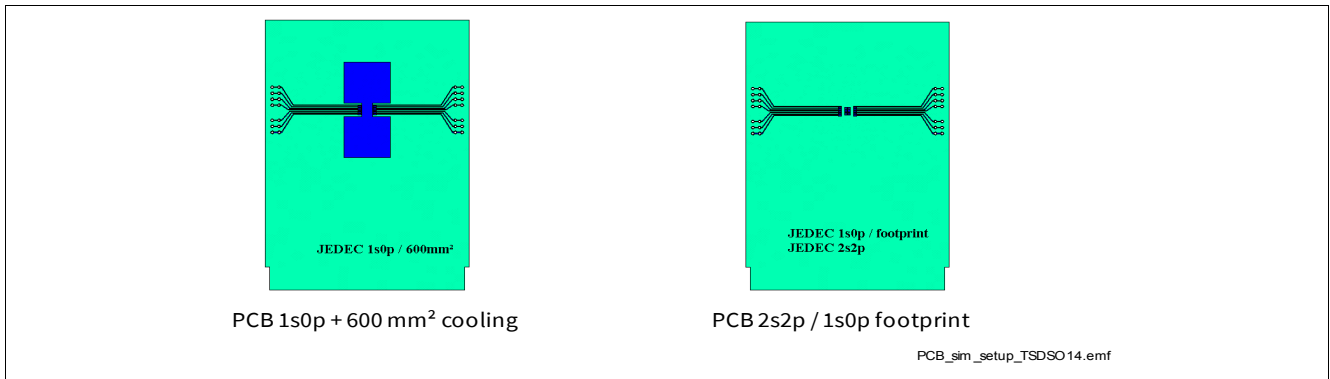


**Figure 5 1s0p PCB Cross Section**

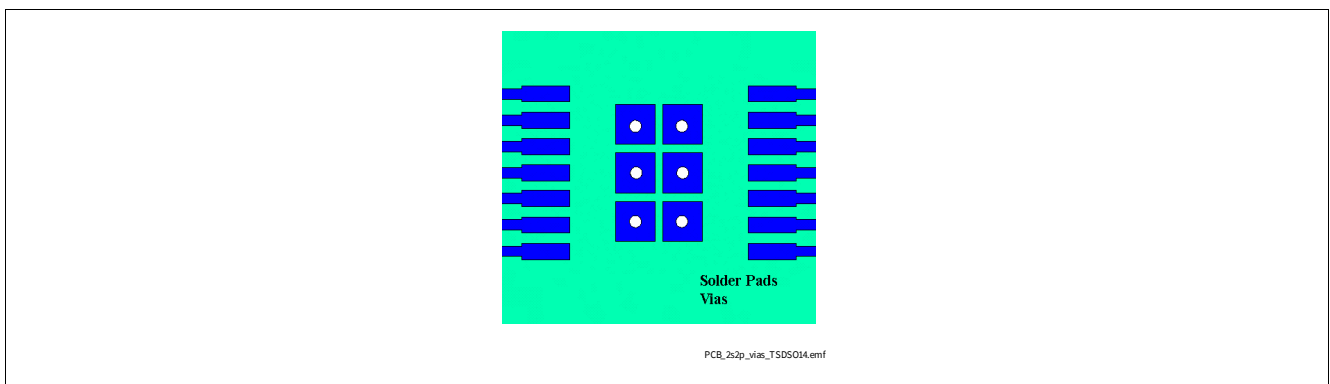


**Figure 6 2s2p PCB Cross Section**

**General Product Characteristics**



**Figure 7 PCB setup for thermal simulations**



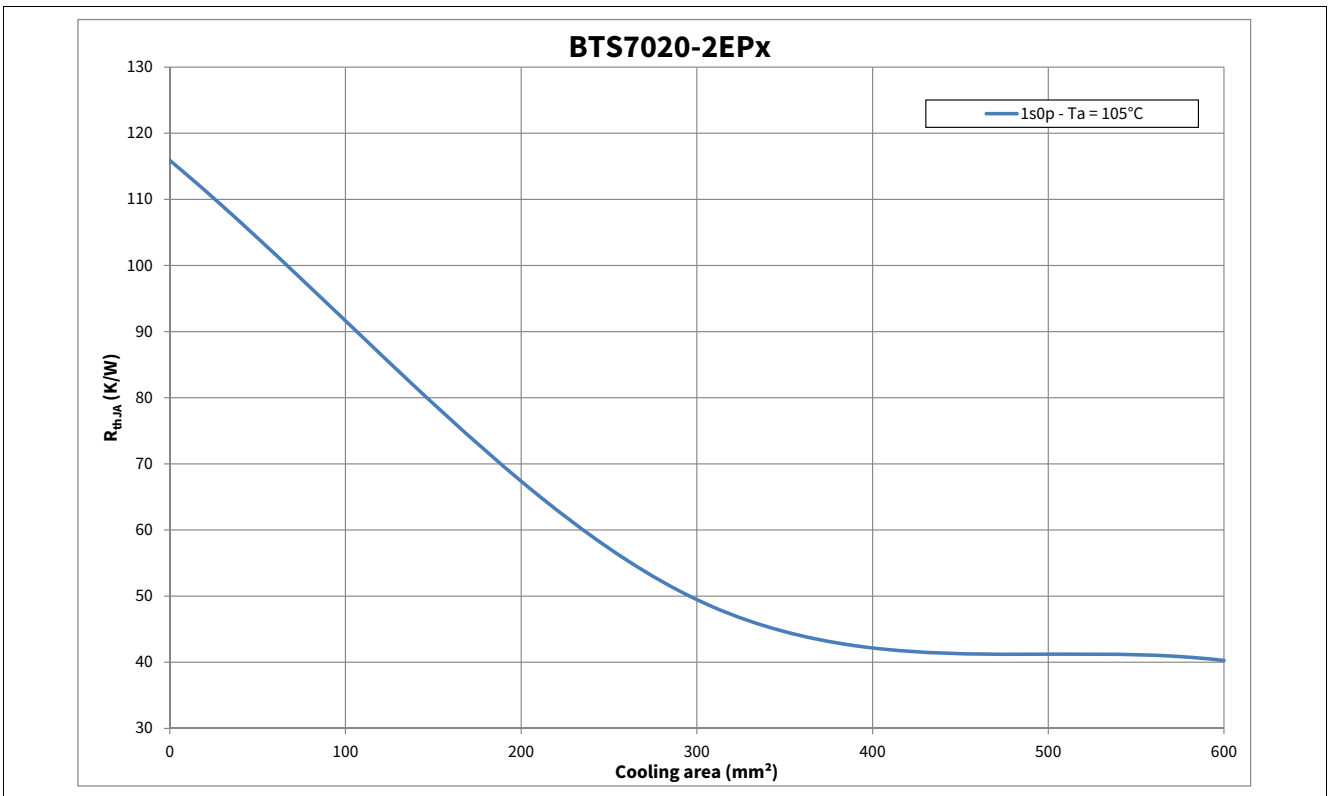
**Figure 8 Thermal vias on PCB for 2s2p PCB setup**

**4.4.2 Thermal Impedance**

**General Product Characteristics**



**Figure 9 Typical Thermal Impedance. PCB setup according Chapter 4.4.1**



**Figure 10 Thermal Resistance on 1s0p PCB with various cooling surfaces**

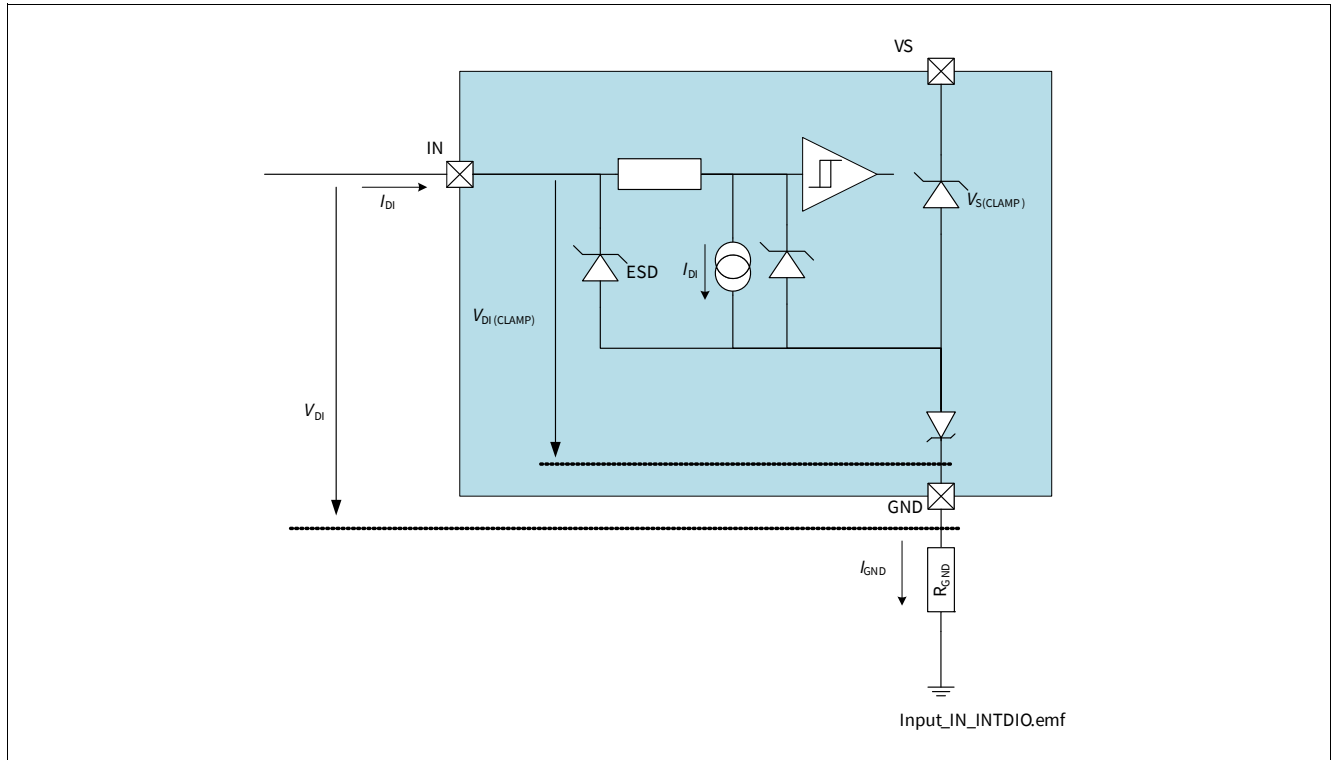
Logic Pins

## 5 Logic Pins

The device has 4 digital pins for direct control.

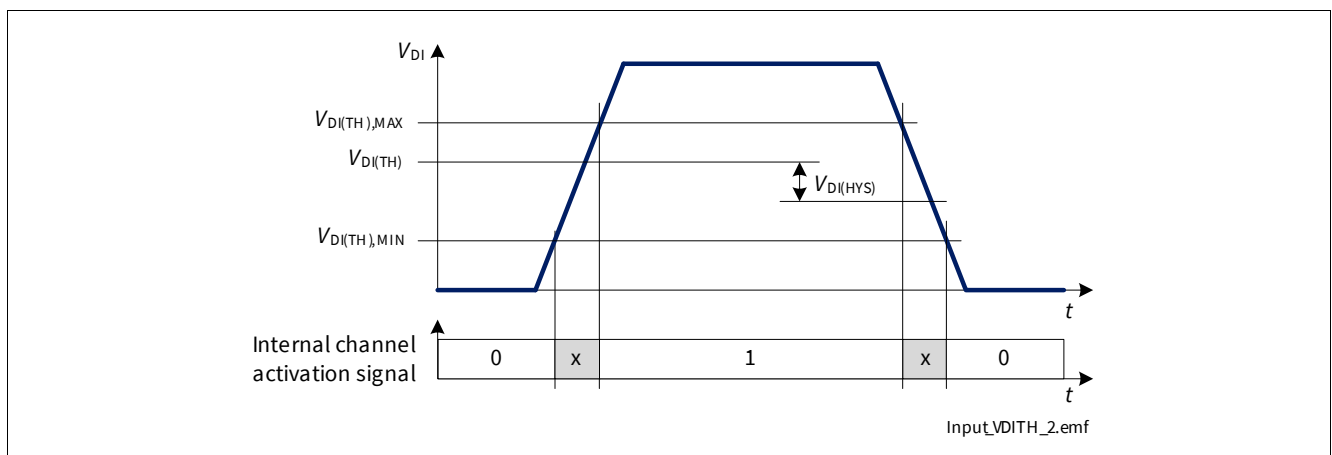
### 5.1 Input Pins (INn)

The input pins IN0, IN1 activate the corresponding output channel. The input circuitry is compatible with 3.3V and 5V micro controller. The electrical equivalent of the input circuitry is shown in **Figure 11**. In case the pin is not used, it must be connected with a 10 kΩ resistor either to GND pin or to module ground.



**Figure 11** Input circuitry

The logic thresholds for “low” and “high” states are defined by parameters  $V_{DI(TH)}$  and  $V_{DI(HYS)}$ . The relationship between these two values is shown in **Figure 12**. The voltage  $V_{IN}$  needed to ensure a “high” state is always higher than the voltage needed to ensure a “low” state.



**Figure 12** Input Threshold voltages and hysteresis

## **5.2 Diagnosis Pin**

The Diagnosis Enable (DEN) pin controls the diagnosis circuitry and the protection circuitry. When DEN pin is set to “high”, the diagnosis is enabled (see [Chapter 9.2](#) for more details). When it is set to “low”, the diagnosis is disabled (IS pin is set to high impedance).

The Diagnosis Selection (DSEL) pin selects the channel where diagnosis is performed (see [Chapter 9.1.1](#)).

The transition from “high” to “low” of DEN pin clears the protection latch of the channel selected with DSEL pin depending on the logic state of IN pin and DEN pulse length (see [Chapter 8.3](#) for more details). The internal structure of diagnosis pins is the same as the one of input pins. See [Figure 11](#) for more details.



**Logic Pins**

**5.3 Electrical Characteristics Logic Pins**

$V_S = 6\text{ V to }18\text{ V}$ ,  $T_J = -40\text{ °C to }+150\text{ °C}$

Typical values:  $V_S = 13.5\text{ V}$ ,  $T_J = 25\text{ °C}$

Digital Input (DI) pins = IN, DEN, DSEL

**Table 7 Electrical Characteristics: Logic Pins - General**

| Parameter                       | Symbol           | Values |      |      | Unit          | Note or Test Condition   | Number    |
|---------------------------------|------------------|--------|------|------|---------------|--|-----------|
|                                 |                  | Min.   | Typ. | Max. |               |  |           |
| Digital Input Voltage Threshold | $V_{DI(TH)}$     | 0.8    | 1.3  | 2    | V             | See <a href="#">Figure 11</a> and <a href="#">Figure 12</a>  | P_5.4.0.1 |
| Digital Input Clamping Voltage  | $V_{DI(CLAMP1)}$ | –      | 7    | –    | V             | <sup>1)</sup><br>$I_{DI} = 1\text{ mA}$<br>See <a href="#">Figure 11</a> and <a href="#">Figure 12</a> | P_5.4.0.2 |
| Digital Input Clamping Voltage  | $V_{DI(CLAMP2)}$ | 6.5    | 7.5  | 8.5  | V             | $I_{DI} = 2\text{ mA}$<br>See <a href="#">Figure 11</a> and <a href="#">Figure 12</a>                  | P_5.4.0.3 |
| Digital Input Hysteresis        | $V_{DI(HYS)}$    | –      | 0.25 | –    | V             | <sup>1)</sup><br>See <a href="#">Figure 11</a> and <a href="#">Figure 12</a>                           | P_5.4.0.4 |
| Digital Input Current (“high”)  | $I_{DI}$         | 2      | 10   | 25   | $\mu\text{A}$ | $V_{DI} = 2\text{ V}$<br>See <a href="#">Figure 11</a> and <a href="#">Figure 12</a>                   | P_5.4.0.5 |
| Digital Input Current (“low”)   | $I_{DI}$         | 2      | 10   | 25   | $\mu\text{A}$ | $V_{DI} = 0.8\text{ V}$<br>See <a href="#">Figure 11</a> and <a href="#">Figure 12</a>                 | P_5.4.0.6 |

1) Not subject to production test - specified by design

## 6 Power Supply

The BTS7020-2EPA is supplied by  $V_S$ , which is used for the internal logic as well as supply for the power output stages.  $V_S$  has an undervoltage detection circuit, which prevents the activation of the power output stages and diagnosis in case the applied voltage is below the undervoltage threshold.

### 6.1 Operation Modes

BTS7020-2EPA has the following operation modes:

- Sleep mode
- Active mode
- Stand-by mode

The transition between operation modes is determined according to these variables:

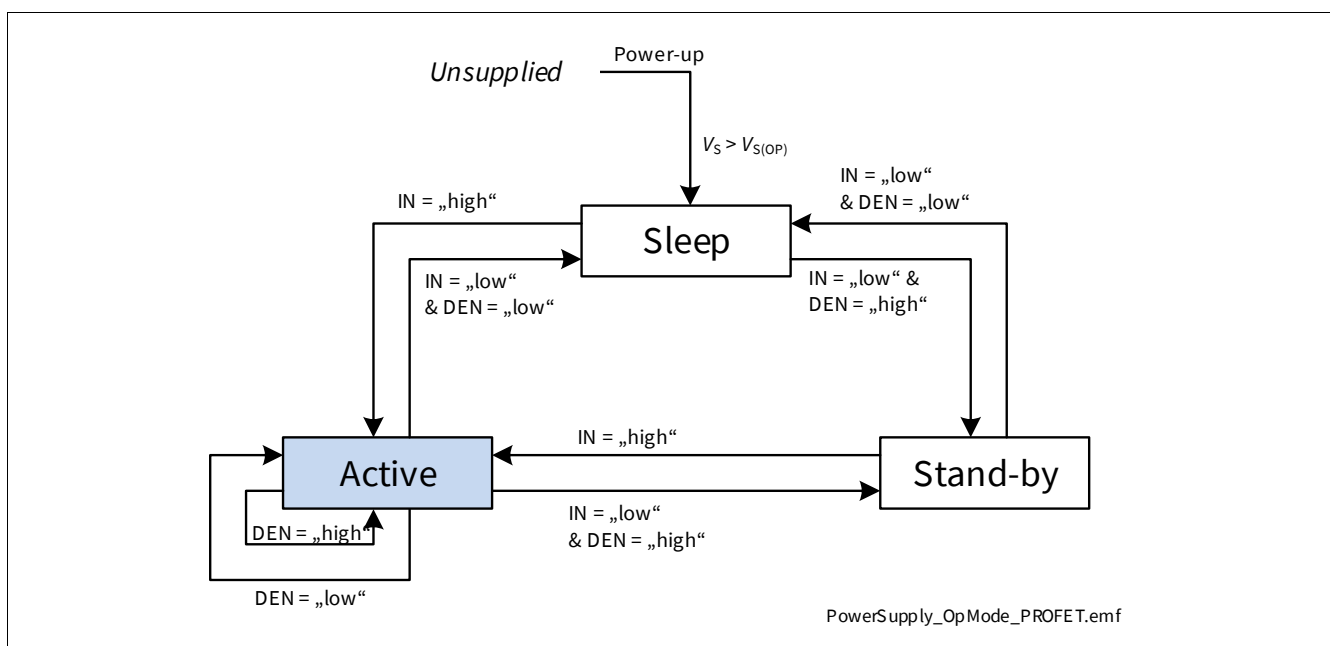
- logic level at INn pins
- logic level at DEN pin

The state diagram including the possible transitions is shown in **Figure 13**. The behavior of BTS7020-2EPA as well as some parameters may change in dependence from the operation mode of the device. Furthermore, due to the undervoltage detection circuitry which monitors  $V_S$  supply voltage, some changes within the same operation mode can be seen accordingly.

There are three parameters describing each operation mode of BTS7020-2EPA:

- status of the output channel
- status of the diagnosis
- current consumption at VS pin (measured by  $I_{VS}$  in Sleep mode,  $I_{GND}$  in all other operative modes)

**Table 8** shows the correlation between operation modes,  $V_S$  supply voltage, and the state of the most important functions (channel status, diagnosis).



**Figure 13 Operation Mode State Diagram**

**Power Supply**

**Table 8 Device function in relation to operation modes and  $V_S$  voltage**

| Operative Mode | Function  | $V_S$ in undervoltage | $V_S$ not in undervoltage      |
|----------------|-----------|-----------------------|--------------------------------|
| Sleep          | Channels  | OFF                   | OFF                            |
|                | Diagnosis | OFF                   | OFF                            |
| Active         | Channels  | OFF                   | available                      |
|                | Diagnosis | OFF                   | available in OFF and ON states |
| Stand-by       | Channels  | OFF                   | OFF                            |
|                | Diagnosis | OFF                   | available in OFF state         |

**6.1.1 Unsupplied**

In this state, the device is either unsupplied (no voltage applied to VS pin) or the supply voltage is below the undervoltage threshold.

**6.1.2 Power-up**

The Power-up condition is entered when the supply voltage ( $V_S$ ) is applied to the device. The supply is rising until it is above the undervoltage threshold  $V_{S(OP)}$  therefore the internal power-on signals are set.

**6.1.3 Sleep mode**

The device is in Sleep mode when all Digital Input pins (INn, DEN, DSEL) are set to “low”. When BTS7020-2EPA is in Sleep mode, all outputs are OFF. The current consumption is minimum (see parameter  $I_{VS(SLEEP)}$ ). No Overtemperature or Overload protection mechanism is active when the device is in Sleep mode. The device can go in Sleep mode only if the protection is not active (counter = 0, see [Chapter 8.3.1](#) for further details).

**6.1.4 Stand-by mode**

The device is in Stand-by mode as long as DEN pin is set to “high” while input pins are set to “low”. All channels are OFF therefore only Open Load in OFF diagnosis is possible. Depending on the load condition, either a fault current  $I_{IS(Fault)}$  or an Open Load in OFF current  $I_{IS(OLOFF)}$  may be present at IS pin. In such situation, the current consumption of the device is increased.

**6.1.5 Active mode**

Active mode is the normal operation mode of BTS7020-2EPA. The device enters Active mode as soon as one IN pin is set to “high”. Device current consumption is specified with  $I_{GND(Active)}$  (measured at GND pin because the current at VS pin includes the load current). Overload, Overtemperature and Overvoltage protections are active. Diagnosis is available.

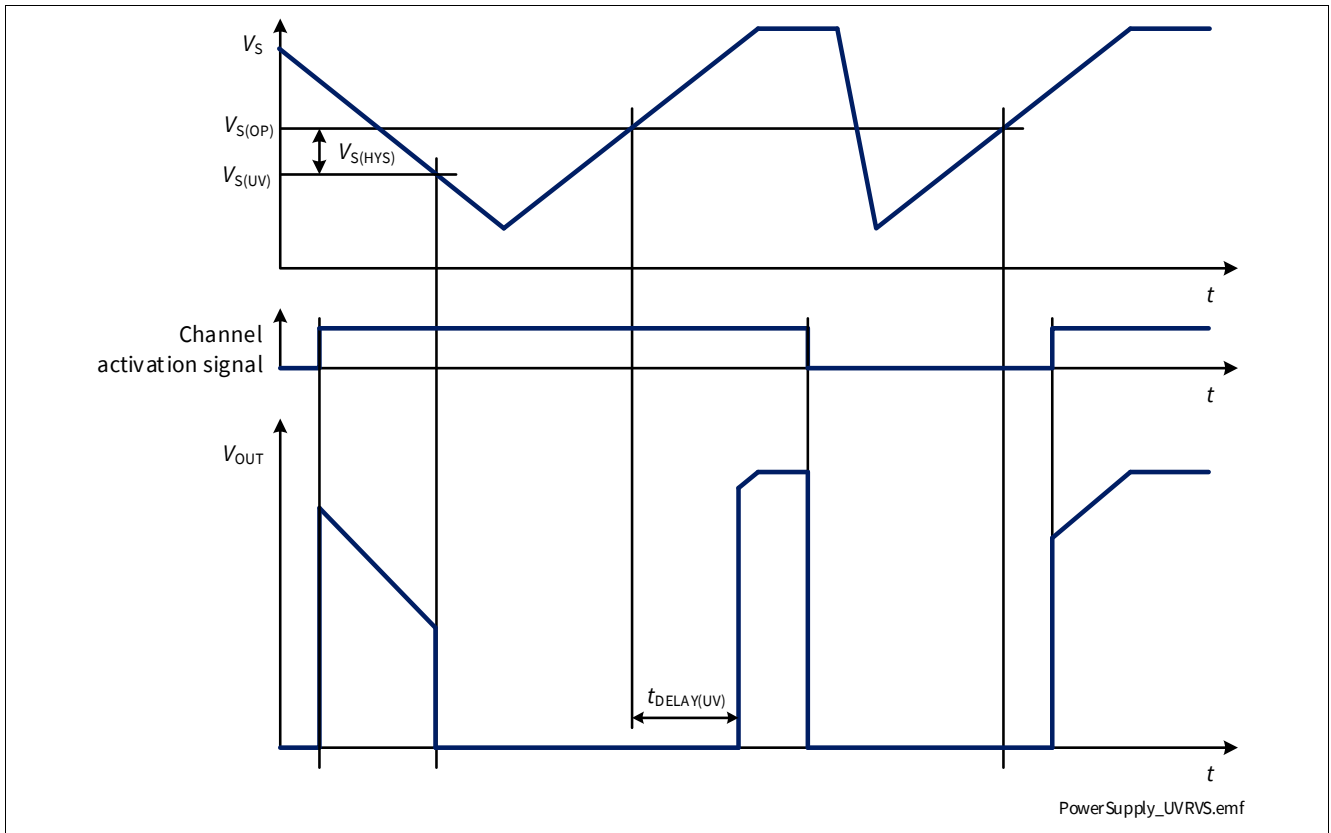
**6.2 Undervoltage on  $V_S$**

Between  $V_{S(OP)}$  and  $V_{S(UV)}$  the undervoltage mechanism is triggered. If the device is operative (in Active mode) and the supply voltage drops below the undervoltage threshold  $V_{S(UV)}$ , the internal logic switches OFF the output channels.

As soon as the supply voltage  $V_S$  is above the operative threshold  $V_{S(OP)}$ , the channels having the corresponding input pin set to “high” are switched ON again. The restart is delayed with a time  $t_{DELAY(UV)}$  which protects the device in case the undervoltage condition is caused by a short circuit event (according to AEC-Q100-012), as shown in [Figure 14](#).

**Power Supply**

If the device is in Sleep mode and one input is set to “high”, the corresponding channel is switched ON if  $V_S > V_{S(OP)}$  without waiting for  $t_{DELAY(UV)}$ .



**Figure 14**  $V_S$  undervoltage behavior

**Power Supply**

**6.3 Electrical Characteristics Power Supply**

$V_S = 6\text{ V to }18\text{ V}$ ,  $T_J = -40\text{ °C to }+150\text{ °C}$

Typical values:  $V_S = 13.5\text{ V}$ ,  $T_J = 25\text{ °C}$

Typical resistive loads connected to the outputs for testing (unless otherwise specified):

$R_L = 3.3\ \Omega$

**Table 9 Electrical Characteristics: Power Supply - General**

| Parameter  | Symbol          | Values |      |      | Unit | Note or Test Condition   | Number    |
|--|-----------------|--------|------|------|------|--|-----------|
|  |                 | Min.   | Typ. | Max. |      |  |           |
| <b>VS pin</b>  |                 |        |      |      |      |  |           |
| Power Supply Undervoltage Shutdown                           | $V_{S(UV)}$     | 1.8    | 2.3  | 3.1  | V    | $V_S$ decreasing<br>IN = "high"<br>From $V_{DS} \leq 0.5\text{ V}$ to<br>$V_{DS} = V_S$<br>See <a href="#">Figure 14</a> | P_6.4.0.1 |
| Power Supply Minimum Operating Voltage                       | $V_{S(OP)}$     | 2.0    | 3.0  | 4.1  | V    | $V_S$ increasing<br>IN = "high"<br>From $V_{DS} = V_S$ to<br>$V_{DS} \leq 0.5\text{ V}$<br>See <a href="#">Figure 14</a> | P_6.4.0.3 |
| Power Supply Undervoltage Shutdown Hysteresis                | $V_{S(HYS)}$    | –      | 0.7  | –    | V    | <sup>1)</sup><br>$V_{S(OP)} - V_{S(UV)}$<br>See <a href="#">Figure 14</a>  | P_6.4.0.6 |
| Power Supply Undervoltage Recovery Time                      | $t_{DELAY(UV)}$ | 2.5    | 5    | 7.5  | ms   | $dV_S/dt \leq 0.5\text{ V}/\mu\text{s}$<br>$V_S \geq -1\text{ V}$<br>See <a href="#">Figure 14</a>                       | P_6.4.0.7 |
| Breakdown Voltage between GND and VS Pins in Reverse Battery | $-V_{S(REV)}$   | 16     | –    | 30   | V    | <sup>1)</sup><br>$I_{GND(REV)} = 7\text{ mA}$<br>$T_J = 150\text{ °C}$   | P_6.4.0.9 |

1) Not subject to production test - specified by design

**6.4 Electrical Characteristics Power Supply - product specific**

**6.4.1 BTS7020-2EPA**

**Power Supply**

**Table 10 Electrical Characteristics: Power Supply BTS7020-2EPA**

| Parameter  | Symbol              | Values |      |      | Unit          | Note or Test Condition   | Number    |
|--|---------------------|--------|------|------|---------------|--|-----------|
|  |                     | Min.   | Typ. | Max. |               |  |           |
| Power Supply Current Consumption in Sleep Mode with Loads at $T_J \leq 85\text{ °C}$ | $I_{VS(SLEEP)_85}$  | –      | 0.03 | 0.6  | $\mu\text{A}$ | 1)<br>$V_S = 18\text{ V}$<br>$V_{OUT} = 0\text{ V}$<br>IN = DEN = “low”<br>$T_J \leq 85\text{ °C}$ | P_6.5.4.1 |
| Power Supply Current Consumption in Sleep Mode with Loads at $T_J = 150\text{ °C}$   | $I_{VS(SLEEP)_150}$ | –      | 4    | 16   | $\mu\text{A}$ | $V_S = 18\text{ V}$<br>$V_{OUT} = 0\text{ V}$<br>IN = DEN = “low”<br>$T_J = 150\text{ °C}$         | P_6.5.4.2 |
| Operating Current in Active Mode (all Channels ON)                                   | $I_{GND(ACTIVE)}$   | –      | 3    | 4    | mA            | $V_S = 18\text{ V}$<br>IN = DEN = “high”   | P_6.5.4.3 |
| Operating Current in Stand-by Mode   | $I_{GND(STBY)}$     | –      | 1.2  | 1.8  | mA            | $V_S = 18\text{ V}$<br>IN = “low”<br>DEN = “high”  | P_6.5.4.5 |

1) Not subject to production test - specified by design

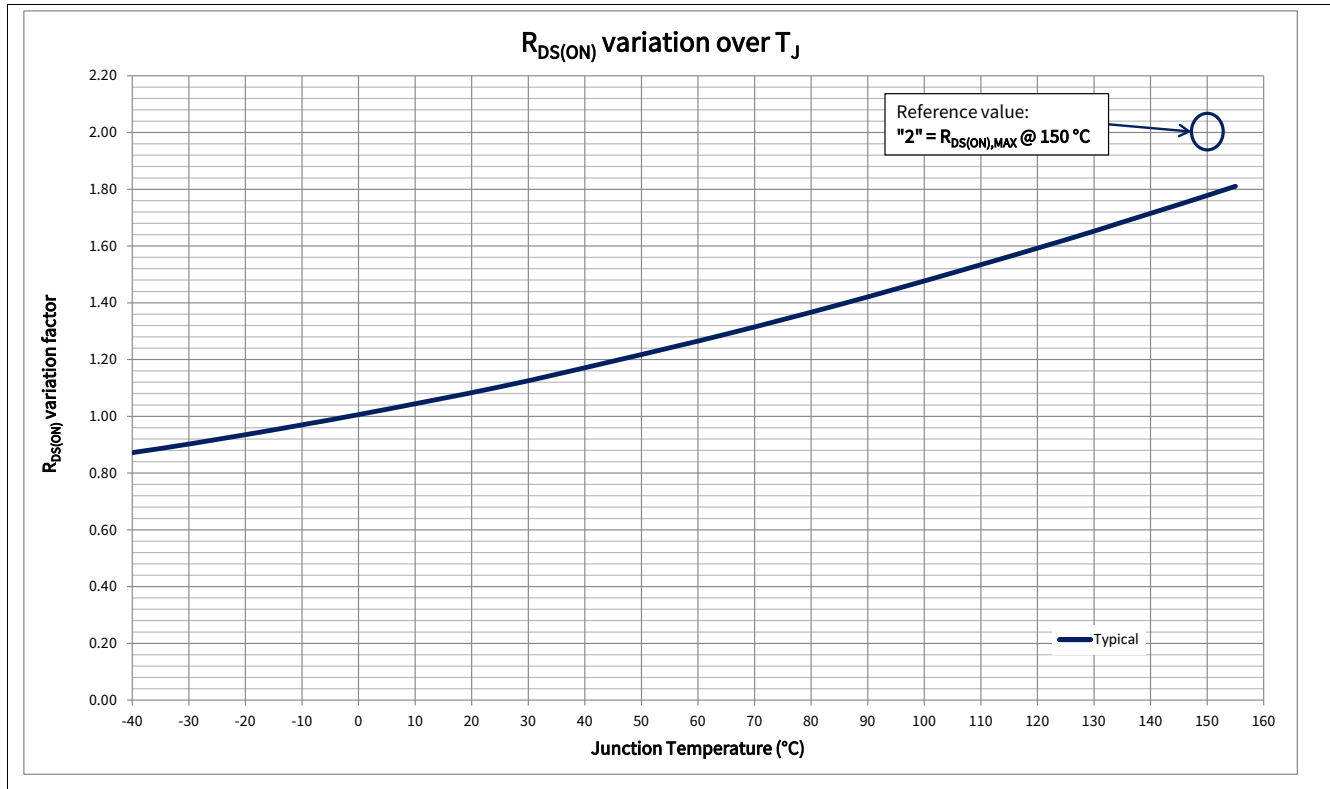
Power Stages

## 7 Power Stages

The high-side power stages are built using a N-channel vertical Power MOSFET with charge pump.

### 7.1 Output ON-State Resistance

The ON-state resistance  $R_{DS(ON)}$  depends mainly on junction temperature  $T_J$ . **Figure 15** shows the variation of  $R_{DS(ON)}$  across the whole  $T_J$  range. The value “2” on the y-axis corresponds to the maximum  $R_{DS(ON)}$  measured at  $T_J = 150\text{ °C}$ .



**Figure 15**  $R_{DS(ON)}$  variation factor

The behavior in Reverse Polarity is described in [Chapter 8.4.1](#).

### 7.2 Switching loads

#### 7.2.1 Switching Resistive Loads

When switching resistive loads, the switching times and slew rates shown in **Figure 16** can be considered. The switch energy values  $E_{ON}$  and  $E_{OFF}$  are proportional to load resistance and times  $t_{ON}$  and  $t_{OFF}$ .



Power Stages

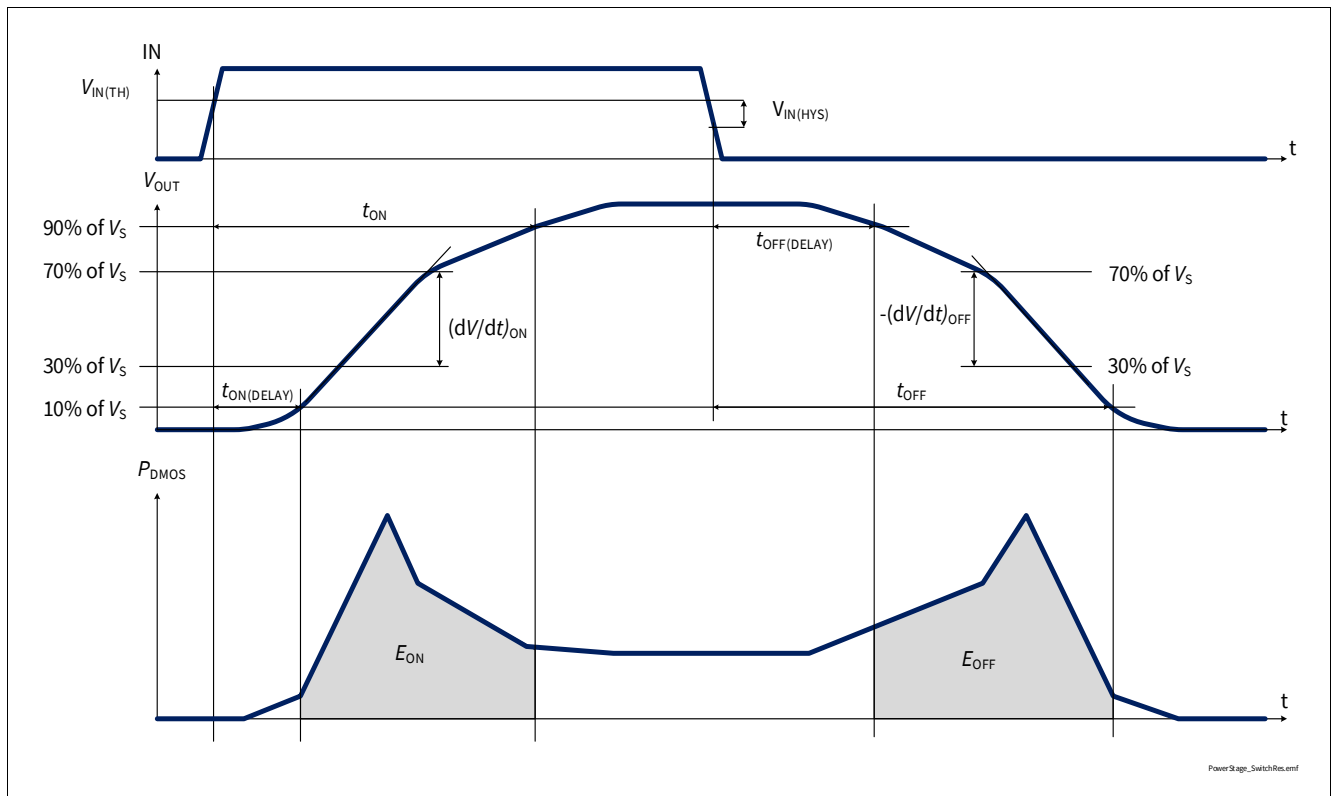


Figure 16 Switching a Resistive Load

### 7.2.2 Switching Inductive Loads

When switching OFF inductive loads with high-side switches, the voltage  $V_{OUT}$  drops below ground potential, because the inductance intends to continue driving the current. To prevent the destruction of the device due to overvoltage, a voltage clamp mechanism is implemented. The clamping structure limits the negative output voltage so that  $V_{DS} = V_{DS(CLAMP)}$ . **Figure 17** shows a concept drawing of the implementation. The clamping structure protects the device in all operation modes listed in **Chapter 6.1**.

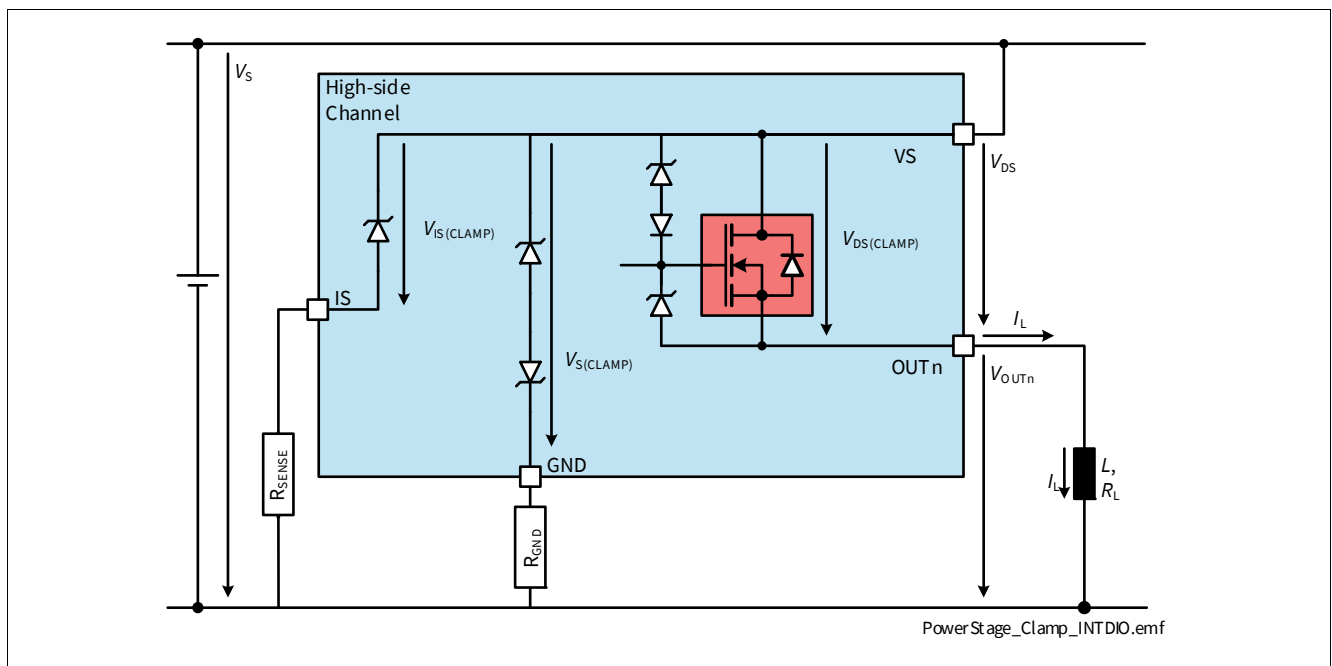


Figure 17 Output Clamp concept

**Power Stages**

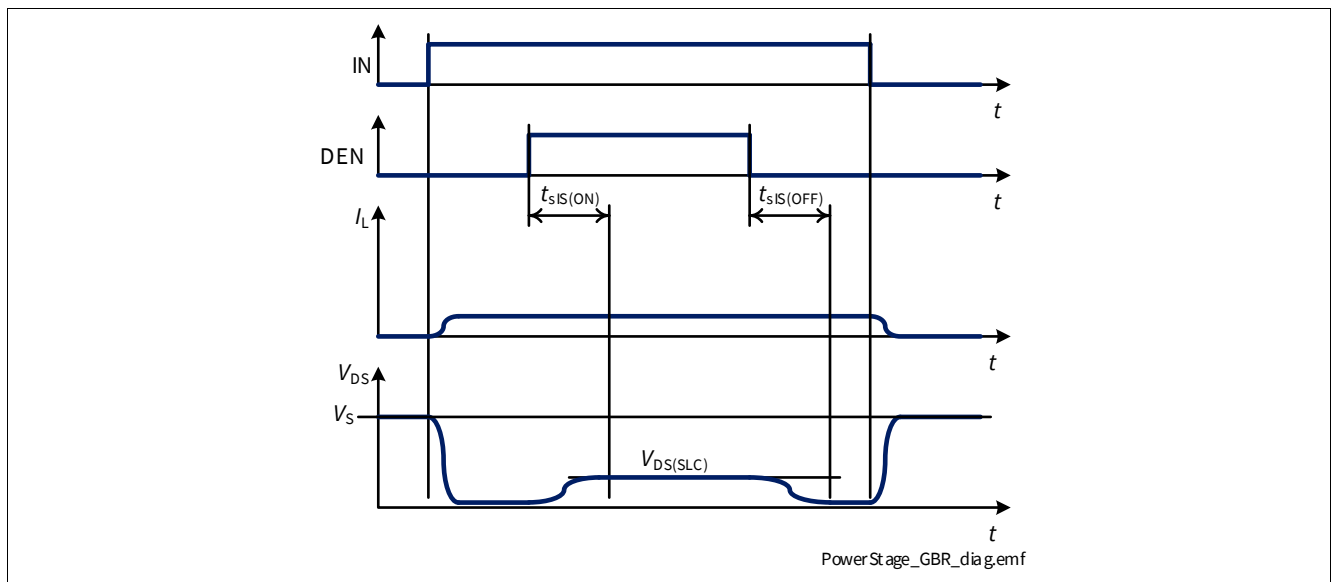
During demagnetization of inductive loads, energy has to be dissipated in BTS7020-2EPA. The energy can be calculated with **Equation (7.1)**:

$$E = V_{DS(CLAMP)} \cdot \left[ \frac{V_S - V_{DS(CLAMP)}}{R_L} \cdot \ln \left( 1 - \frac{R_L \cdot I_L}{V_S - V_{DS(CLAMP)}} \right) + I_L \right] \cdot \frac{L}{R_L} \quad (7.1)$$

The maximum energy, therefore the maximum inductance for a given current, is limited by the thermal design of the component.

**7.2.3 Output Voltage Limitation**

To increase the current sense accuracy,  $V_{DS}$  voltage is monitored. When the output current  $I_L$  decreases while the channel is diagnosed (DEN pin set to “high”, channel selected with DSEL pins - see **Figure 18**) bringing  $V_{DS}$  equal or lower than  $V_{DS(SLC)}$ , the output DMOS gate is partially discharged. This increases the output resistance so that  $V_{DS} = V_{DS(SLC)}$  even for very small output currents. The  $V_{DS}$  increase allows the current sensing circuitry to work more efficiently, providing better  $k_{ILIS}$  accuracy for output current in the low range.



**Figure 18 Output Voltage Limitation activation during diagnosis**

**7.3 Advanced Switching Characteristics**

**7.3.1 Inverse Current behavior**

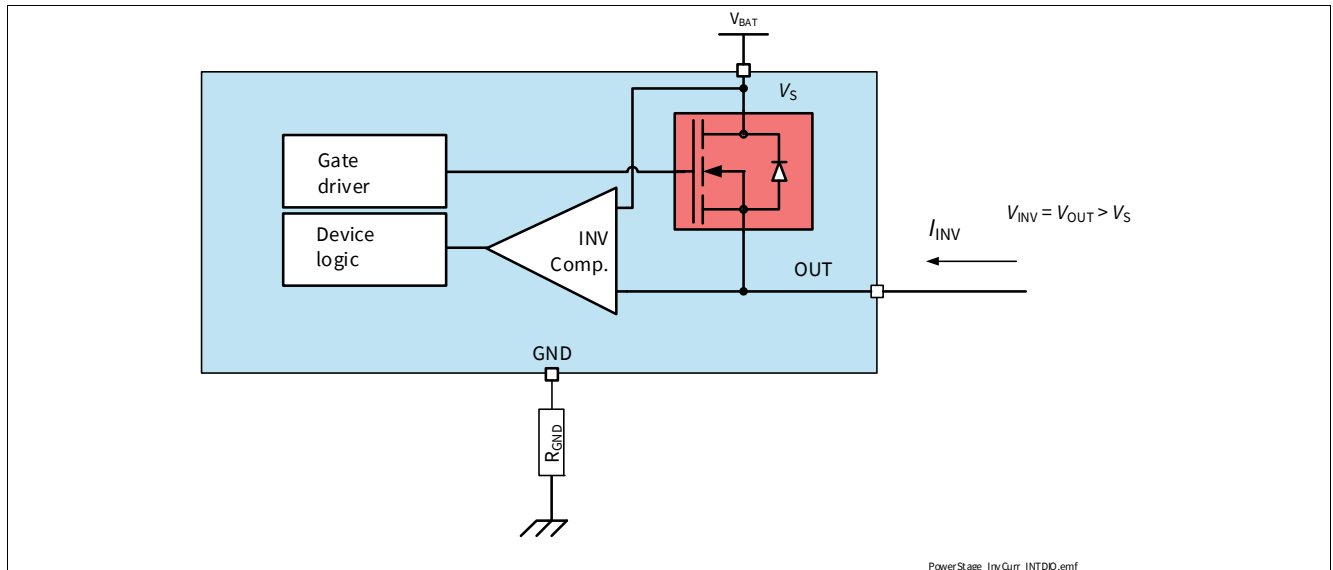
When  $V_{OUT} > V_S$ , a current  $I_{INV}$  flows into the power output transistor (see **Figure 19**). This condition is known as “Inverse Current”.

If the channel is in OFF state, the current flows through the intrinsic body diode generating high power losses therefore an increase of overall device temperature. This may lead to a switch OFF of unaffected channels due to Overtemperature. If the channel is in ON state,  $R_{DS(INV)}$  can be expected and power dissipation in the output stage is comparable to normal operation in  $R_{DS(ON)}$ .

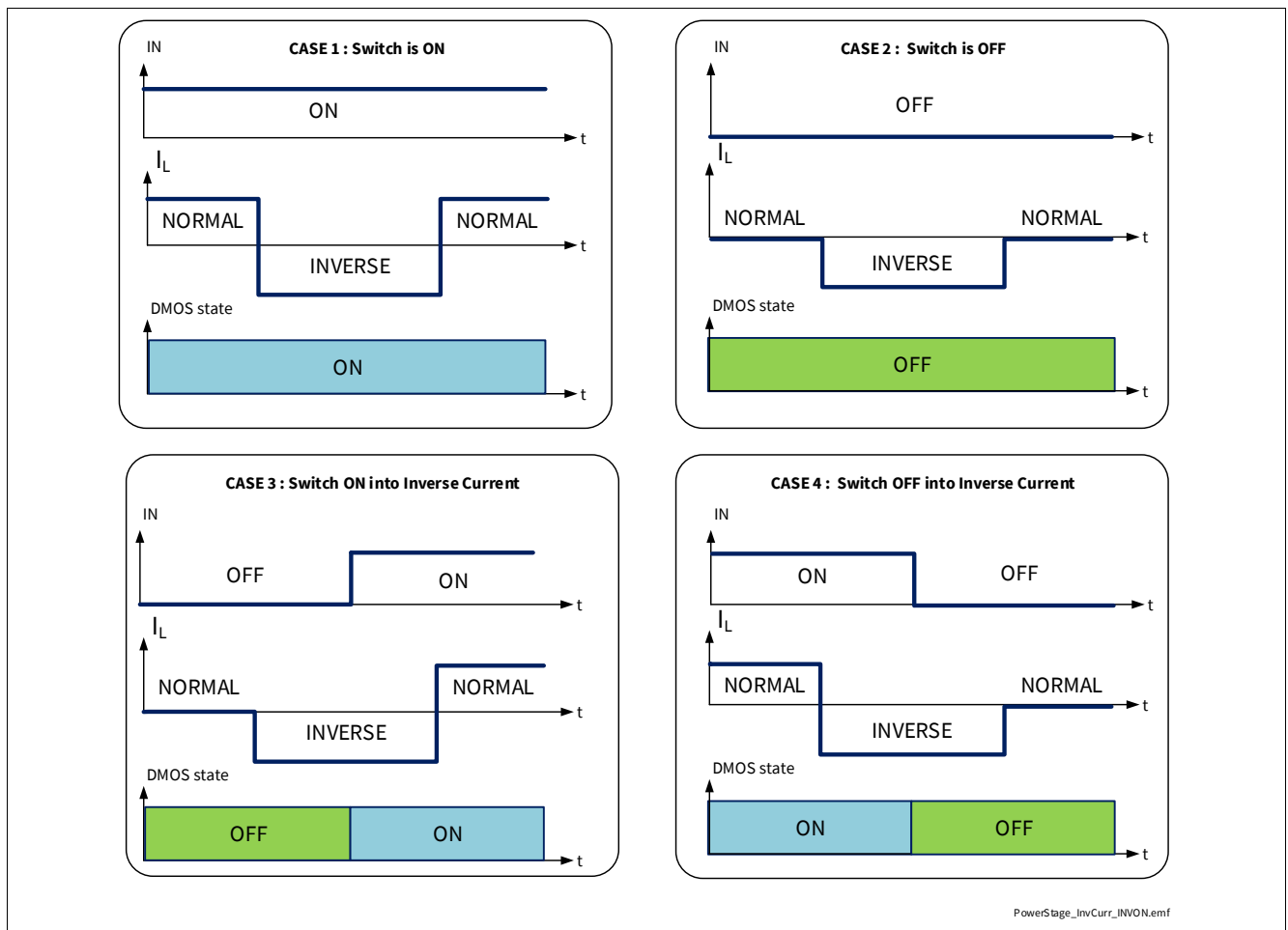
During Inverse Current condition, the channel remains in ON or OFF state as long as  $I_{INV} < I_{L(INV)}$ . If one channel has inverse current applied, the neighbor channel is not influenced, meaning that switching ON and OFF timings, protection (Overcurrent, Overtemperature) and current sensing ( $k_{ILIS}$ ) are still within specified limits.

**Power Stages**

With InverseON, it is possible to switch ON the channel during Inverse Current condition as long as  $I_{INV} < I_{L(INV)}$  (see **Figure 20**).



**Figure 19 Inverse Current Circuitry**



**Figure 20 InverseON - Channel behavior in case of applied Inverse Current**

**Power Stages**

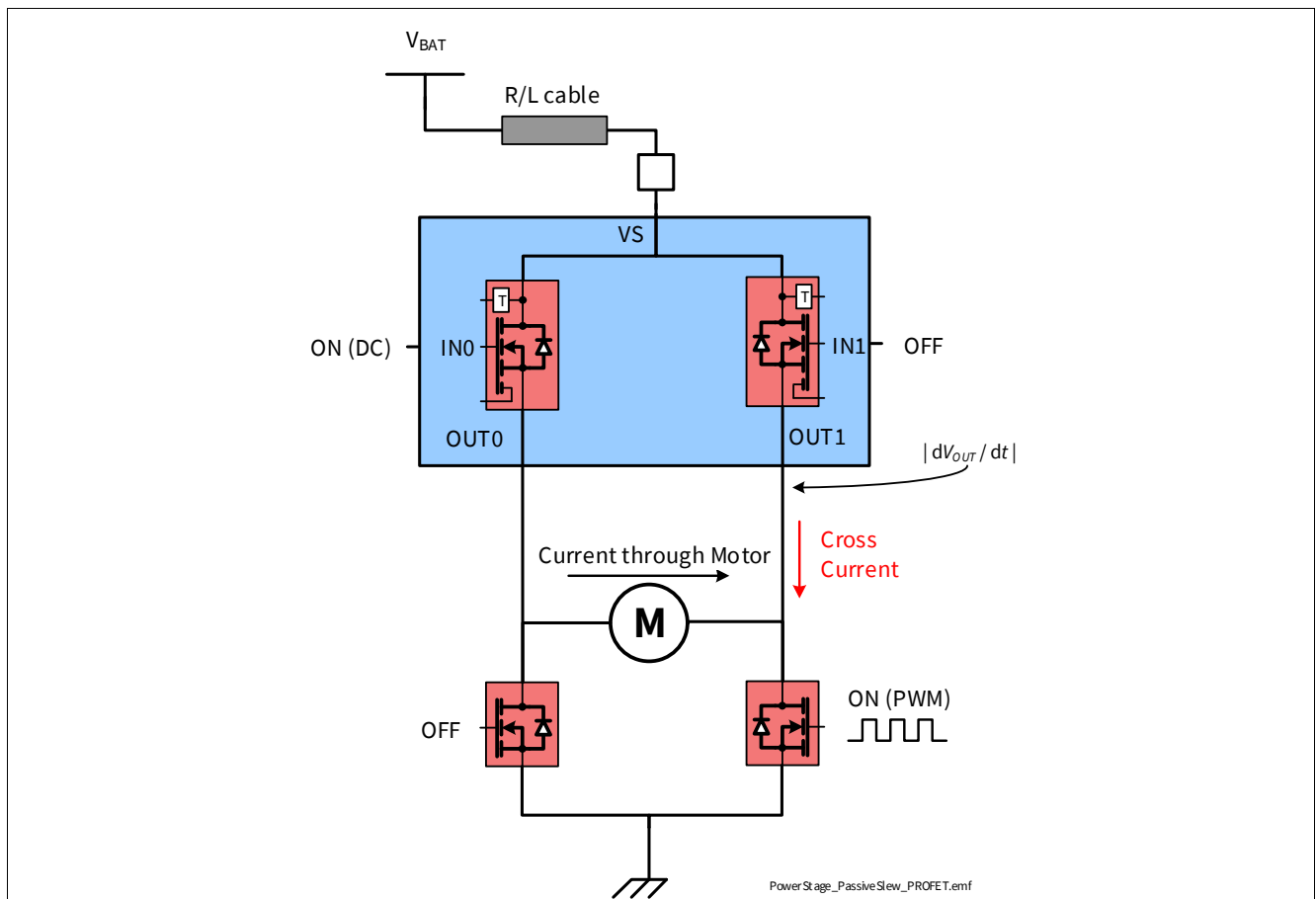
*Note: No protection mechanism like Overtemperature or Overload protection is active during applied Inverse Currents.*

**7.3.2 Switching Channels in Parallel**

In case of appearance of a short circuit with connected in parallel to drive a single load, it may happen that the two channels switch OFF asynchronously, therefore bringing an additional thermal stress to the channel that switches OFF last. For this reason it is not recommended to use the device with channels in parallel.

**7.3.3 Cross Current robustness with H-Bridge configuration**

When BTS7020-2EPA is used as high-side switch e.g. in a bridge configuration (therefore paired with a low-side switch as shown in **Figure 21**), the maximum slew rate applied to the output by the low-side switch must be lower than  $|dV_{OUT} / dt|$ . Otherwise the output stage may turn ON in linear mode (not in  $R_{DS(ON)}$ ) while the low-side switch is commutating. This creates an unprotected over heating situation for the DMOS due to the cross-conduction current.



**Figure 21 High-Side switch used in Bridge configuration**